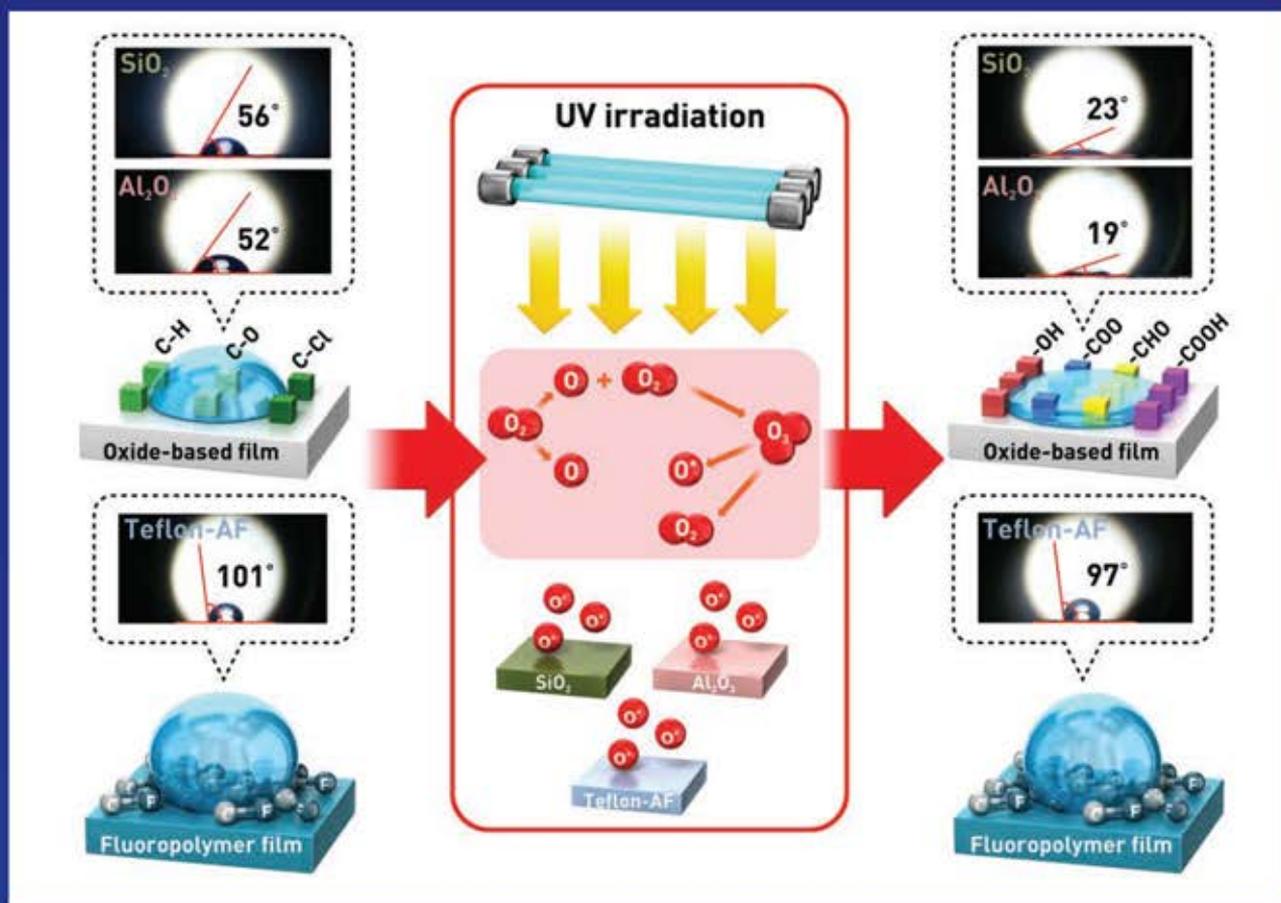


SCIENCE OF ADVANCED MATERIALS

Editor-in-Chief: Prof. Ahmad Umar



COVER

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